



US00D409929S

# United States Patent [19]

Fisher et al.

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## [54] ELECTRICAL TEST PROBE

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[73] Assignee: **Fluke Corporation**, Everett, Wash.

[\*\*] Term: **14 Years**

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[51] **LOC (6) Cl.** ..... **10-04**

[52] **U.S. Cl.** ..... **D10/78**

[58] **Field of Search** ..... D10/78; 324/72.5, 324/149, 156, 508, 509, 538; 340/815.74

## [56] **References Cited**

### U.S. PATENT DOCUMENTS

D. 391,503 3/1998 Van Dyk ..... D10/78

## OTHER PUBLICATIONS

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*Primary Examiner*—Antoine Duval Davis

## [57] **CLAIM**

The ornamental design for an electrical test probe, as shown.

## **DESCRIPTION**

FIG. 1 is a top, front, and right side perspective view of an electrical test probe showing our new design; FIG. 2 is a front elevational view thereof; FIG. 3 is a right side elevational view thereof; FIG. 4 is a back elevational view thereof; FIG. 5 is a top plan view thereof; and, FIG. 6 a bottom plan view thereof.

The broken line showing is for illustrative purposes only and forms no part of the claimed design.

**1 Claim, 1 Drawing Sheet**

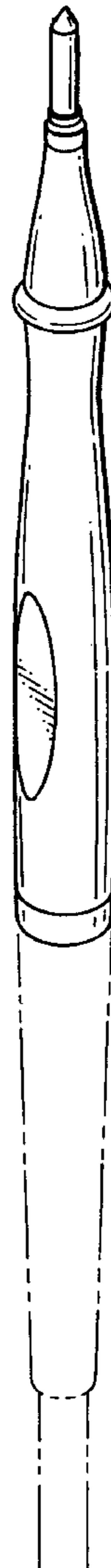


FIG. 1

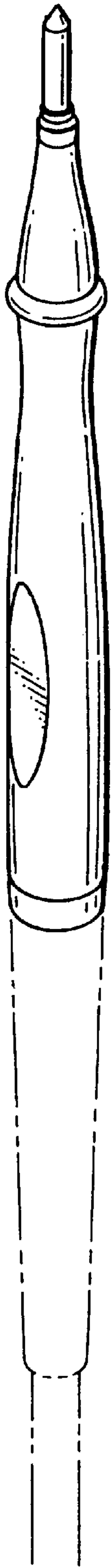


FIG. 2



FIG. 3



FIG. 4

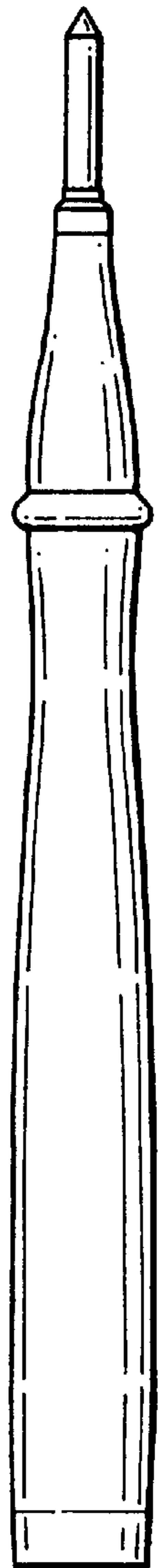


FIG. 5



FIG. 6

